

# BSC252N10NSF G-VB Datasheet N-Channel 100-V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>(BR)DSS</sub> (V)	$r_{DS(on)}(\Omega)$				
100	0.017 at V <sub>GS</sub> = 10 V	30			

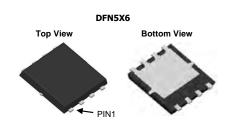
#### **FEATURES**

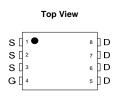
- TrenchFET® Power MOSFET
- 175 °C Junction Temperature
- Low Thermal Resistance Package
- 100 % R<sub>g</sub> Tested

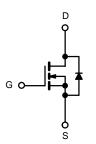


#### **APPLICATIONS**

• Isolated DC/DC Converters







N-Channel MOSFET

ABSOLUTE MAXIMUM RATING	<b>iS</b> (T <sub>A</sub> = 25 °C, u	nless other	wise noted)		
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-source voltage		V <sub>DS</sub>	100	V	
Gate-source voltage		$V_{GS}$	± 20	7 v	
	T <sub>C</sub> = 25 °C		30		
Continuous drain surrent /T 150 °C)	T <sub>C</sub> = 70 °C	1 .	19		
Continuous drain current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	l <sub>D</sub>	10 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C	1	8.5 <sup>b, c</sup>	_	
Pulsed drain current (t = 100 μs)		I <sub>DM</sub>	75	A	
Continuous source drain diade surrent	T <sub>C</sub> = 25 °C	,	56		
Continuous source-drain diode current	T <sub>A</sub> = 25 °C	l <sub>S</sub>	4.5 b, c		
Single pulse avalanche current		I <sub>AS</sub>	20		
Single pulse avalanche energy	L = 0.1 mH	E <sub>AS</sub>	20	mJ	
	T <sub>C</sub> = 25 °C		60		
Maximum naurar dissination	T <sub>C</sub> = 70 °C	Б	40	W	
Maximum power dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	5 b, c		
	T <sub>A</sub> = 70 °C	•	3.2 b, c		
Operating junction and storage temperature range		T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Soldering recommendations (peak temperature) <sup>c</sup>			260	7	

THERMAL RESISTANCE RATINGS							
PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT		
Maximum junction-to-ambient b	t ≤ 10 s	$R_{thJA}$	20	25	°C/W		
Maximum junction-to-case (drain)	Steady state	$R_{thJC}$	1.6	2	C/VV		

#### Notes

- a. Package limited
- b. Surface mounted on 1" x 1" FR4 board
- c. t = 10 s

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SPECIFICATIONS (T <sub>J</sub> = 25 °C, unless otherwise noted)								
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT		
Static				1		1		
Drain-source breakdown voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100	-	-	V		
V <sub>DS</sub> temperature coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = 10 mA	-	81	-	mV/°(		
V <sub>GS(th)</sub> temperature coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA	-	-7.5	-			
Gate-source threshold voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	3	-	5	V		
Gate-source leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	100	nA		
Zero gate voltage drain current	la a a	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	1	μА		
Zero gate voltage drain edirent	I <sub>DSS</sub>	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 70 ^{\circ}\text{C}$	-		15			
On-state drain current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \geq 10~V,~V_{GS} = 10~V$	40	-	-	Α		
Drain-source on-state resistance <sup>a</sup>	D	$V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$	i	0.0170	ı	Ω		
Diditi-source off-state resistance	R <sub>DS(on)</sub>	$V_{GS} = 7.5 \text{ V}, I_D = 10 \text{ A}$	-	0.0200	-			
Forward transconductance <sup>a</sup>	9 <sub>fs</sub>	$V_{DS} = 15 \text{ V}, I_D = 10 \text{ A}$	=.	46	=.	S		
Dynamic <sup>b</sup>								
Input capacitance	C <sub>iss</sub>		-	1470	-	pF		
Output capacitance	C <sub>oss</sub>	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	132	-			
Reverse transfer capacitance	C <sub>rss</sub>		-	11.2	-			
Total gate charge	Qg	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$	-	20	-	nC		
			-	15	-			
Gate-source charge	Q <sub>qs</sub>	$V_{DS} = 50 \text{ V}, V_{GS} = 7.5 \text{ V}, I_D = 10 \text{ A}$	-	6.45	-			
Gate-drain charge	$Q_{gd}$		-	3.5	-			
Output charge	Q <sub>oss</sub>	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}$	-	22	-			
Gate resistance	R <sub>q</sub>	f = 1 MHz	0.2	0.76	1.4	Ω		
Turn-on delay time	t <sub>d(on)</sub>		-	12	24			
Rise time	t <sub>r</sub>	$V_{DD} = 50 \text{ V}, R_L = 5 \Omega, I_D \cong 10 \text{ A},$	-	5	10	1		
Turn-off delay time	t <sub>d(off)</sub>	$V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$	-	19	38			
Fall time	t <sub>f</sub>		-	5	10			
Turn-on delay time	t <sub>d(on)</sub>		-	15	30	ns		
Rise time	t <sub>r</sub>	$V_{DD} = 50 \text{ V}, R_{I} = 5 \Omega, I_{D} \approx 10 \text{ A},$	-	6	12			
Turn-off delay time	t <sub>d(off)</sub>	$V_{GEN} = 7.5 \text{ V}, R_q = 1 \Omega$	-	19	38			
Fall time	t <sub>f</sub>	-	-	5	10			
Drain-Source Body Diode Characteristi								
Continuous source-drain diode current	Is	T <sub>C</sub> = 25 °C	-	_	56.8			
Pulse diode forward current	I <sub>SM</sub>	<u> </u>	_	_	80	A		
Body diode voltage	V <sub>SD</sub>	I <sub>S</sub> = 5 A, V <sub>GS</sub> = 0 V	_	0.78	1.1	V		
Body diode reverse recovery time	t <sub>rr</sub>	.5 5 . , . 45 5 .	_	43	86	ns		
Body diode reverse recovery charge	Q <sub>rr</sub>		_	72	144	nC		
Reverse recovery fall time	t <sub>a</sub>	$I_F = 10 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$	_	33	-	110		
Reverse recovery rise time	t <sub>b</sub>			10		ns		

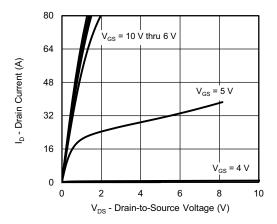
#### Notes

- a. Pulse test; pulse width  $\leq 300~\mu s,\,duty~cycle \leq 2~\%$
- b. Guaranteed by design, not subject to production testing

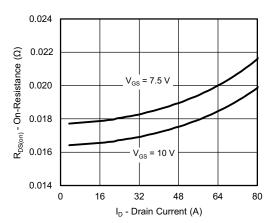
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



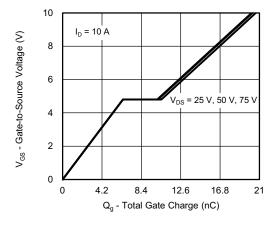
#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



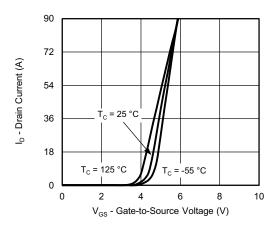
#### **Output Characteristics**



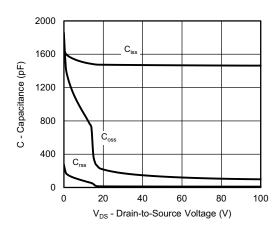
On-Resistance vs. Drain Current and Gate Voltage



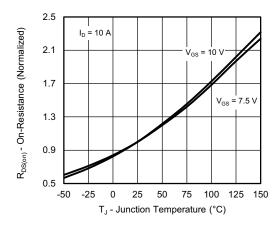
**Gate Charge** 



**Transfer Characteristics** 



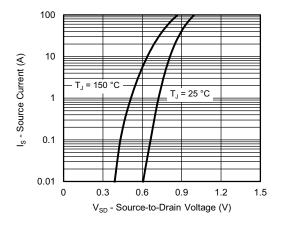
Capacitance



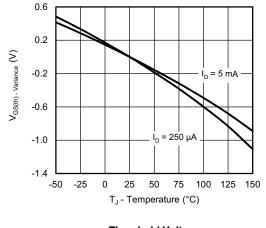
On-Resistance vs. Junction Temperature



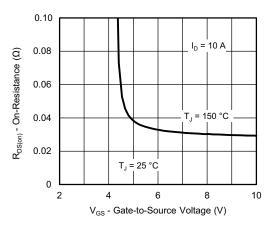
#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



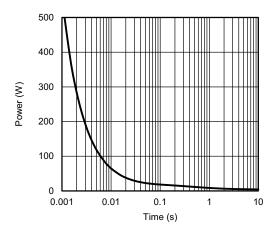
Source-Drain Diode Forward Voltage



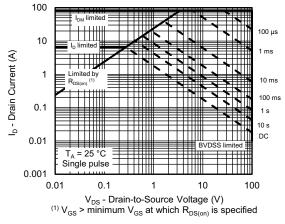
**Threshold Voltage** 



On-Resistance vs. Gate-to-Source Voltage



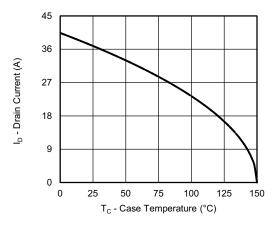
Single Pulse Power, Junction-to-Ambient



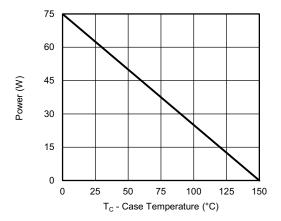
Safe Operating Area, Junction-to-Ambient

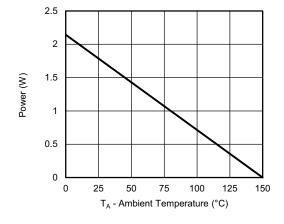


#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



#### Current Derating <sup>a</sup>





Power, Junction-to-Case

Power, Junction-to-Ambient

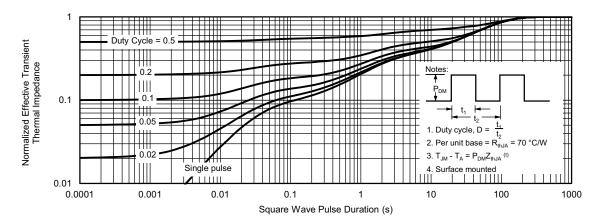
#### Note

a. The power dissipation  $P_D$  is based on  $T_J$  max. = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit

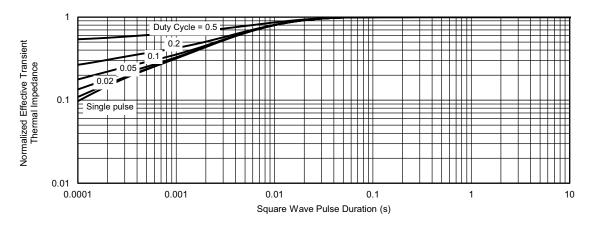
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#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



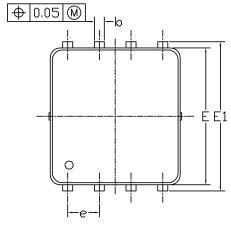
#### Normalized Thermal Transient Impedance, Junction-to-Ambient

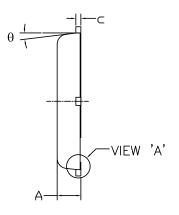


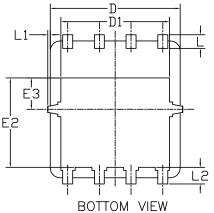
Normalized Thermal Transient Impedance, Junction-to-Case

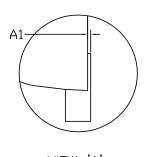


DFN5x6\_8L\_EP1\_P PACKAGE OUTLIN



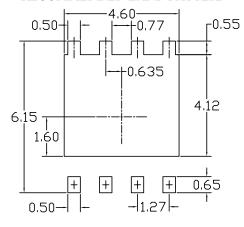






<u>VIEW 'A'</u> (SCALE 5:1)

#### RECOMMENDED LAND PATTERN



CVA (DOLC	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES		
SYMBOLS	MIN	NOM	MAX	MIN	NOM	MAX
A	0.85	0. 95	1.00	0.033	0.037	0.039
Al	0.00		0.05	0.000		0.002
b	0.30	0.40	0.50	0.012	0.016	0.020
c	0. 15	0. 20	0. 25	0.006	0.008	0.010
D	5. 10	5. 20	5. 30	0. 201	0. 205	0. 209
D1	4. 25	4. 35	4. 45	0. 167	0.171	0. 175
Е	5. 45	5. 55	5. 65	0. 215	0. 219	0. 222
E1	5. 95	6.05	6. 15	0. 234	0. 238	0. 242
E2	3. 525	3.625	3. 725	0.139	0. 143	0. 147
E3	1. 175	1. 275	1. 375	0.046	0.050	0.054
e	1. 27 BSC			0.050 BSC		
L	0.45	0. 55	0.65	0.018	0.022	0.026
L1	0		0. 15	0		0.006
L2	0.68 REF			0.027 REF		
θ	0°		10°	0°		10°

#### **NOTE**

- 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
- 2. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

UNIT: mm



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